

EVENT BASED TEST SYSTEM HAVING IMPROVED
SEMICONDUCTOR CHARACTERIZATION MAP

Abstract of the Disclosure

5 An event based test system having an improved
characterization tool for semiconductor device testing. The
characterization map provides multi-dimensional views of
device performance for debug of the design, and
identification of performance weaknesses. The
10 characterization map tool exploits the capabilities of the
event based test system. The multi-dimensional views
include a checkerboard map such as displaying pins versus
time, a shmoo plot showing pass-fail boundary points
relative to predetermined parameters, or a margin map
15 showing a pass/fail range for pins corresponding with timing
changes in one or more events.

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